

N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR

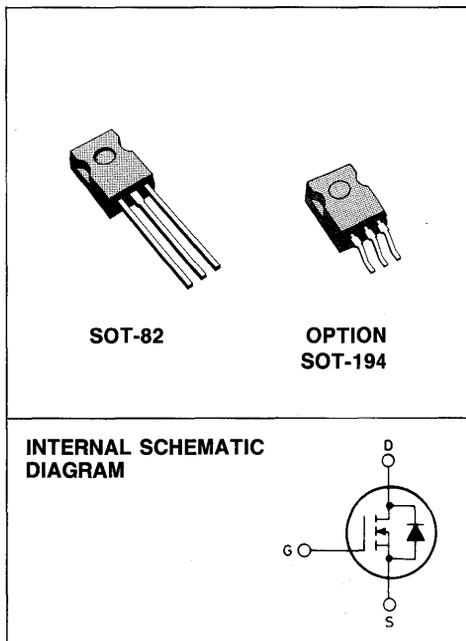
TYPE	V _{DSS}	R _{DS(on)}	I _D
SGSP230	450 V	3 Ω	2.5 A

- HIGH SPEED SWITCHING APPLICATIONS
- HIGH VOLTAGE - 450V FOR OFF-LINE SMPS
- ULTRA FAST SWITCHING FOR OPERATION AT > 100KHz
- EASY DRIVE FOR REDUCED COST AND SIZE

INDUSTRIAL APPLICATIONS:

- SWITCHING POWER SUPPLIES
- MOTOR CONTROLS

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and very fast switching times make this POWER MOS transistor ideal for high speed switching applications. Typical applications include switching power supplies, uninterruptible power supplies and motor speed control.



ABSOLUTE MAXIMUM RATINGS

V _{DS}	Drain-source voltage (V _{GS} = 0)	450	V
V _{DGR}	Drain-gate voltage (R _{GS} = 20 KΩ)	450	V
V _{GS}	Gate-source voltage	±20	V
I _D	Drain current (cont.) at T _c = 25°C	2.5	A
I _D	Drain current (cont.) at T _c = 100°C	1.5	A
I _{DM} (*)	Drain current (pulsed)	10	A
I _{DLM} (*)	Drain inductive current, clamped	10	A
P _{tot}	Total dissipation at T _c < 25°C	50	W
	Derating factor	0.4	W/°C
T _{stg}	Storage temperature	-65 to 150	°C
T _j	Max. operating junction temperature	150	°C

(*) Pulse width limited by safe operating area

THERMAL DATA

$R_{thj - case}$	Thermal resistance junction-case	max	2.5	°C/W
T_L	Maximum lead temperature for soldering purpose		275	°C

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
------------	-----------------	------	------	------	------

OFF

$V_{(BR) DSS}$	Drain-source breakdown voltage	$I_D = 250 \mu A$	$V_{GS} = 0$	450		V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating} \times 0.8$ $T_c = 125^{\circ}C$			250 1000	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 20 V$			± 100	nA

ON (*)

$V_{GS (th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 250 \mu A$	2	4	V
$R_{DS (on)}$	Static drain-source on resistance	$V_{GS} = 10 V$ $I_D = 1.2 A$ $V_{GS} = 10 V$ $I_D = 1.2 A$ $T_c = 100^{\circ}C$			3 6	Ω Ω

DYNAMIC

g_{fs}	Forward transconductance	$V_{DS} = 25 V$	$I_D = 1.2 A$	0.8		mho
C_{iss}	Input capacitance	$V_{DS} = 25 V$ $f = 1 MHz$ $V_{GS} = 0$			340	450 95 50
C_{oss}	Output capacitance					
C_{rss}	Reverse transfer capacitance					

SWITCHING

$t_{d (on)}$	Turn-on time	$V_{DD} = 225 V$	$I_D = 1.2 A$		10	15	ns
t_r	Rise time	$V_i = 10 V$	$R_i = 4.7 \Omega$		25	35	ns
$t_{d (off)}$	Turn-off delay time	(see test circuit)			55	70	ns
t_f	Fall time				25	35	ns

ELECTRICAL CHARACTERISTICS (Continued)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current			2.5	A
$I_{SDM} (*)$	Source-drain current (pulsed)			10	A
V_{SD}	Forward on voltage	$I_{SD} = 2.5 \text{ A}$	$V_{GS} = 0$	1.2	V
t_{rr}	Reverse recovery time	$I_{SD} = 2.5 \text{ A}$ $di/dt = 100 \text{ A}/\mu\text{s}$	$V_{GS} = 0$	340	ns

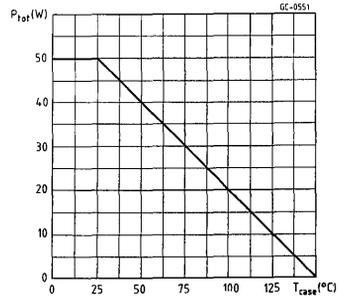
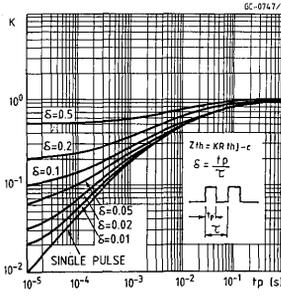
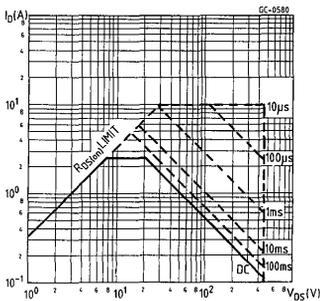
(*) Pulsed: Pulse duration = 300 μs , duty cycle 1.5%

(*) Pulse width limited by safe operating area

Safe operating areas

Thermal impedance

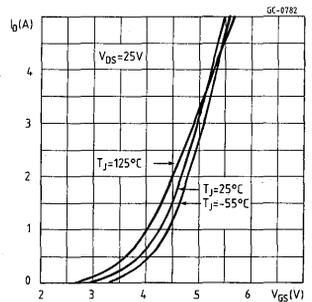
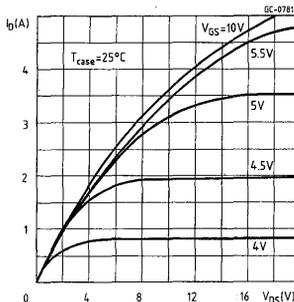
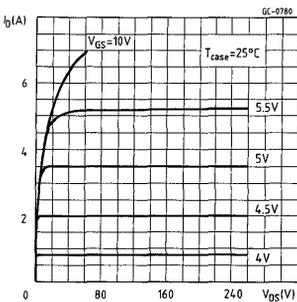
Derating curve



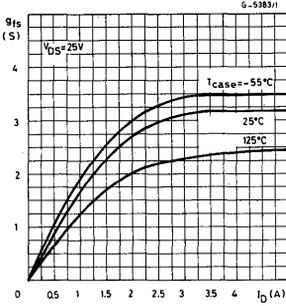
Output characteristics

Output characteristics

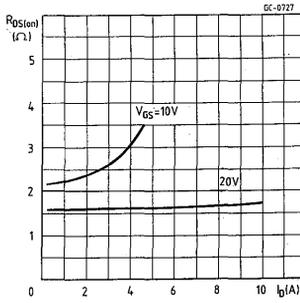
Transfer characteristics



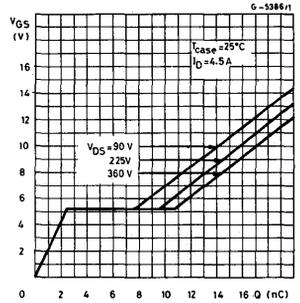
Transconductance



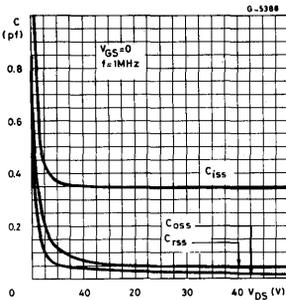
Static drain-source on resistance



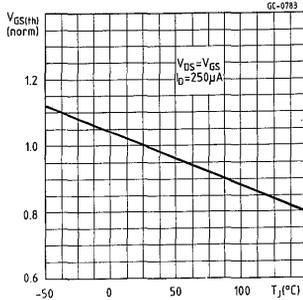
Gate charge vs gate-source voltage



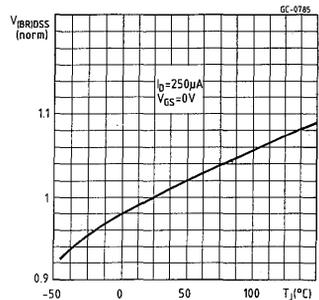
Capacitance variation



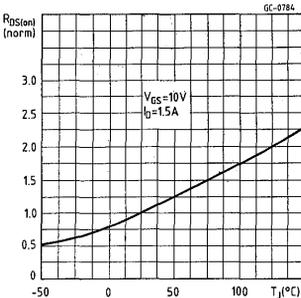
Normalized gate threshold voltage vs temperature



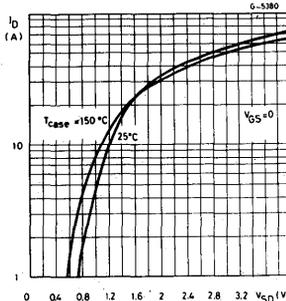
Normalized breakdown voltage vs temperature



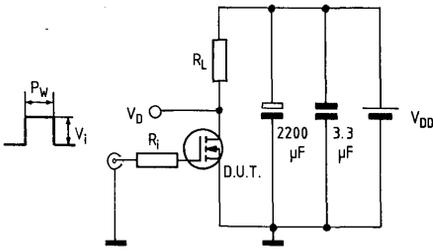
Normalized on resistance vs temperature



Source-drain diode forward characteristics



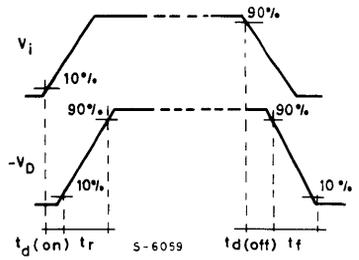
Switching times test circuit for resistive load



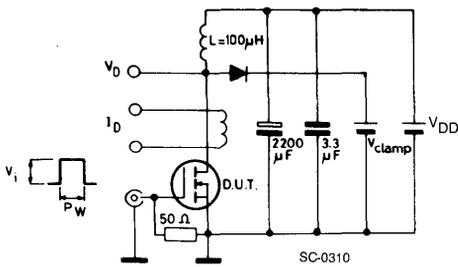
Pulse width $\leq 100 \mu\text{s}$
 Duty cycle $\leq 2\%$

SC-0008/1

Switching time waveforms for resistive load



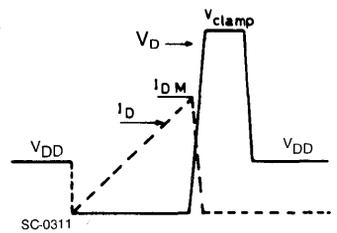
Clamped inductive load test circuit



$V_i = 12 \text{ V}$ - Pulse width: adjusted to obtain specified I_{DM} , $V_{\text{clamp}} = 0.75 V_{(BR) \text{ DSS}}$.

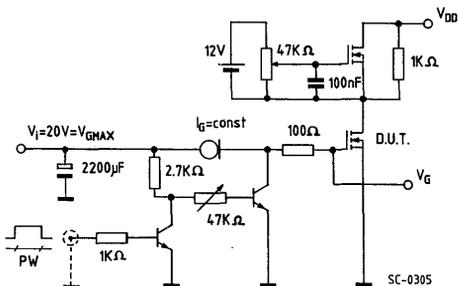
SC-0310

Clamped inductive waveforms



SC-0311

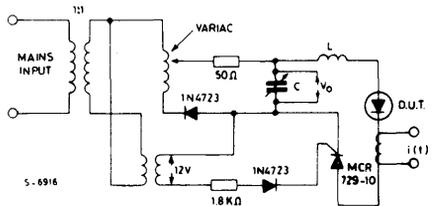
Gate charge test circuit



PW adjusted to obtain required V_G

SC-0305

Body-drain diode t_{rr} measurement
 Jedec test circuit



S-6916